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- Inputs Are TTL-Voltage Compatible
- 3-State Inverting Outputs Drive Bus Lines Directly
- Full Parallel Access for Loading
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic (N) and Ceramic (J) DIPs

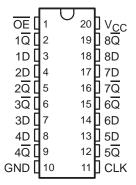
#### description

These octal edge-triggered D-type flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. The devices are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

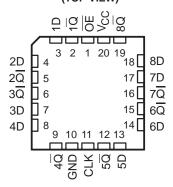
On the positive transition of the clock (CLK) input, the  $\overline{Q}$  outputs are set to the complements of the logic levels set up at the data (D) inputs.

A buffered output-enable ( $\overline{OE}$ ) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

SN54ACT534 ... J OR W PACKAGE SN74ACT534 ... DB, DW, N, OR PW PACKAGE (TOP VIEW)



SN54ACT534 . . . FK PACKAGE (TOP VIEW)



OE does not affect internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ACT534 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to 125°C. The SN74ACT534 is characterized for operation from  $-40^{\circ}$ C to 85°C.



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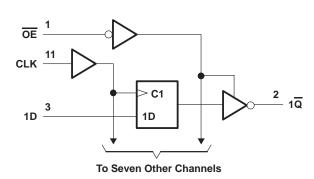
## FUNCTION TABLE (each flip-flop)

	INPUTS	OUTPUT	
OE	CLK	D	Q
L	1	Н	L
L	$\uparrow$	L	Н
L	H or L	Χ	$\overline{Q}_0$
Н	Χ	Χ	Z

#### logic symbol†

#### ΕN **CLK** C1 3 $\nabla$ 1Q 1D 1D 5 2Q 2D 7 6 3D 3Q 8 9 4Q 4D 13 12 5Q 5D 14 15 6Q 6D 16 7D 7Q 18 19 8<del>Q</del> 8D

#### logic diagram (positive logic)



#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>		0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, VO (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ).		
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CO}$		
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )		
Continuous current through V <sub>CC</sub> or GND		
Package thermal impedance, θ <sub>JA</sub> (see Note 2)	: DB package	70°C/W
, ,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	DW package	58°C/W
	N package	69°C/W
	PW package	83°C/W
Storage temperature range, T <sub>sto</sub>		–65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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#### recommended operating conditions (see Note 3)

		SN54A	CT534	T534 SN74ACT534		
		MIN MAX		MIN	MAX	UNIT
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2	2	2		V
VIL	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	Vcc	0	VCC	V
Vo	Output voltage	0	Vcc	0	VCC	V
IOH	High-level output current	2	-24		-24	mA
loL	Low-level output current	30/	24		24	mA
Δt/Δν	Input transition rise or fall rate	0	8	0	8	ns/V
TA	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS	Vaa	T <sub>A</sub> = 25°C			SN54A	CT534	SN74ACT534		UNIT
PARAMETER		VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
	I <sub>OH</sub> = -50 μA	4.5 V	4.4	4.49		4.4		4.4		V
		5.5 V	5.4	5.49		5.4		5.4		
\/a	Jan 24 mA	4.5 V	3.8			3.7		3.76		
VOH	$I_{OH} = -24 \text{ mA}$	5.5 V	4.86			4.7		4.76		
	I <sub>OH</sub> = -50 mA <sup>†</sup>	5.5 V				3.85				
	I <sub>OH</sub> = -75 mA <sup>†</sup>	5.5 V					7	3.85		
	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1		0.1	V
		5.5 V			0.1		0.1		0.1	
\/o	I <sub>OL</sub> = 24 mA	4.5 V			0.36	7	0.5		0.44	
VOL		5.5 V			0.36	2/2/	0.5		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V				70,	1.65			
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V				Q			1.65	
loz	$V_O = V_{CC}$ or GND	5.5 V			±0.25		±5		±2.5	μΑ
lį	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			±0.1		±1		±1	μΑ
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		80		40	μΑ
∆l <sub>CC</sub> ‡	One input at 3.4 V, Other inputs at GND or V <sub>CC</sub>	5.5 V		0.6			1.6		1.5	mA
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		4.5						pF

<sup>†</sup>Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

# timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

		T <sub>A</sub> = 25°C		SN54ACT534		SN74ACT534		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
t <sub>W</sub>	Pulse duration, CLK high or low	3.5		5	100	3.5		ns
t <sub>su</sub>	Setup time, data before CLK↑	3.5		5	716	4		ns
th	Hold time, data after CLK↑	1		3		1.5		ns



<sup>&</sup>lt;sup>‡</sup> This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V<sub>CC</sub>.

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# switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

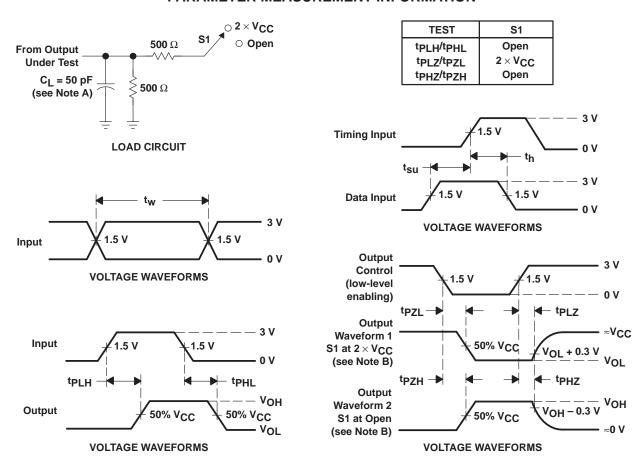
PARAMETER	FROM	FROM TO	T <sub>A</sub> = 25°C		SN54ACT534		SN74ACT534		UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
f <sub>max</sub>			100		85	7	120		MHz
t <sub>PLH</sub>	CLK	CLK Q	2.5	11.5	1.5	14	2	12.5	ns
t <sub>PHL</sub>		α	2	10.5	1.5	13	2	12	115
<sup>t</sup> PZH	ŌĒ	Ια	2.5	12	1.5	14	2	12.5	ns
t <sub>PZL</sub>		α	2	11	1.5	13	2	11.5	115
<sup>t</sup> PHZ	ŌĒ	Ια	1.5	12.5	9.5	14.5	1	13.5	ne
tPLZ	OE	Q	1.5	10.5	1.5	11.5	1	10.5	ns

### operating characteristics, $V_{CC}$ = 5 V, $T_A$ = 25°C

PARAMETER		TEST CO	TYP	UNIT	
C <sub>pd</sub>	Power dissipation capacitance	C <sub>L</sub> = 50 pF,	f = 1 MHz	40	pF

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#### PARAMETER MEASUREMENT INFORMATION



NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz, Z<sub>O</sub> = 50  $\Omega$ ,  $t_r \leq$  2.5 ns,  $t_f \leq$  2.5 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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